CORRECTION

Correction to: Microstructural Characteristics of Oxide Layer Growth on Tin Whisker and Finish Surface

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Correction to:
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In the original publication of the article the sentence in the conclusions section that reads as “Both str crystalline and amorphous structures of SnO₂ were observed” should read as “Both crystalline and amorphous structures of SnO₂ were observed”.

Errors have subsequently been identified in the original publication, and the following correction should be noted:

In the original publication of this article, the Figures 1, 4, 5a, 5b and 7a were published incorrectly. The corrected figures are given in this correction.

The original article can be found online at <https://doi.org/10.1007/s42341-019-00125-7>.

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Fig. 1 FE-SEM images of whisker grown morphology on the pure Sn-plated Cu. **a** After storage at room temperature for 20 years. **b** After storage at 55 °C for 16 months

Fig. 4 The showing of the Pt coating interface at the surface of the Sn whisker after exposure at 55 °C/85% RH for 2 months. **a** Low magnification TEM image showing of the Sn oxide layer formed on the Sn whisker, **b** HR-TEM image and EDP obtained from circled area 'A' in Fig. 3a

Fig. 5 Bright-field and HRTEM image showing the Sn oxide layer formed on the surface after stored at room temperature for 20 years. **a** A layer of 13.5–20.0 nm SnO_2 film on the surface of the Sn finish. Top left figure shows the close-up image of Fig. 4a. **b** The interface at the C coating and crystalline Sn whisker. The interface appears to be incoherent. **c** EELS spectra obtained from positions 1–5 shown in Fig. 4b

Fig. 7 **a** A direct contact image of Sn finish and four point nanoprobe manipulator. **b** I–V curve obtained from the direct contact measurement

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